RELEASE NOTES

Keysight EasyEXPERT group+ Software for PC

Version 6.5.2436.1070

Release Date:	21 November, 2024
Requirements Category: Equipment Firmware revision:	B1500A/B1505A: A.04.00 or later. E5260A/62A/63A/70B: B.01.10 or later B2900A: All revisions. When using firmware license, 3.0 or later is needed. B2900B: All revisions.
File Name:	EasyEXPERT_for_PC.6.5.2436.1070.zip
License:	B150xA-SWS or B150xAU-SWS License Required

New Features and Enhancements

- JEP192 application tests for B1505A/B1506A.

Bug Fixes

- Fixed: [124] Initial test setting optimization of V-gate pulse width for application tests with expanders.

Version 6.4.2312.1715

Release Date:	1 June, 2023
File Name:	EasyEXPERT_for_PC.6.4.2312.1715.zip

New Features and Enhancements

- JEP183/184 application tests for B1505A/B1506A.

Bug Fixes

- Fixed: [587455] Unexpected error 203 occurs on E526xA/70B current sweeping with high voltage compliance.
- Fixed: [45] Unexpected duty check error on B2900 pulsed sweeping.

Version 6.3.2222.6640

Release Date:	15 Sep, 2022
File Name:	EasyEXPERT_for_B1500.6.3.2222.6640.zip

New Features and Enhancements

- [586951] Wants to use ERCMAPFGD command on Direct Control.

Bug Fixes

- Fixed: [586950] Unexpected 'Value cannot be null' error when running application tests on E5260A/62A/63A.
- Fixed: [586952] Hangs up after pressing open all/apply switch/read switch buttons on Switching Matrix Setup dialog.
- Fixed: [586973] Setup text and VAR2 labels are not shown for B2900.

Version 6.3.2209.5850

Released Date:	25 April. 2022
File Name:	EE_for_PC.6.3.2209.5850.zip

Bug Fixes

- Fixed: [586452] Unexpected error 103001 (USB 488 error) when I/V List Sweep delays contain 2 seconds or more.
- Fixed: [586465] Installer fails on updating EasyEXPERT database if it contains corrupt workspace.

Version 6.3.2133.4940

Released Date:	25 Oct. 2021
File Name:	EEasyEXPERT_for_PC.6.3.2133.4940.zip

Bug Fixes

- Fixed: [585137] License management tool cannot show model numbers for B29xxB.
- Fixed: [585250] GDI resource leak on SPGU ALWG waveform editor.
- Fixed: [585258] Quick test hangs up after Matrix Setup when parameter column in the test result list is enabled.
- Fixed: [585489] Cgd(N1272A) stops intermittently when thermometer is enabled.
- Fixed: [585960] Contributed application tests are not shown for B29xxB.

Version 6.3.2042.5845

Released Date:	1 Dec. 2020
File Name:	EasyEXPERT_for_PC.6.3.2042.5845.zip

New Features and Enhancements

- B2900B Classic Test support
- B2900B Tracer Test support

Bug Fixes

- Fixed: [578353] Unexpected exception on exporting measurement data to CSV generated by 6.1 or prior revisions.
- Fixed: [578920] 'Comment out' information is lost on exporting application test definition.
- Fixed: [580714] EasyEXPERT for PC cannot connect to B150xA when connecting just after B150xA boot up.
- Fixed: [584763] Improper default current measurement range for B2900A. [584246] Socially Responsible Technical Nomenclature

Version 6.2.1927.7790

Released Date:	15 Aug. 2019
File Name:	EasyEXPERT_for_PC.6.2.1927.7790.zip

Bug Fixes

- Fixed: [572979] N1285A relay diagnostic test may fail due to oscillation of HVSMU output depending on cable length.
- Fixed: [574002] Unexpected exception on C-V Sweep with two or more SMUs

Version 6.2.1909.3580

Released Date:	25 Apr. 2019
File Name:	-

New Features and Enhancements

- "Not Used" channels on Channel Definition. [199166]
- "Copy & Paste" functions for application test definition contents. [208097]
- Wants to comment out application test definition contents. [208098]
- Wants to run an executable file before measurement, after measurement, and after aborting on repetitive measurement. [364964]
- Secondary (VAR2) sweep step selection for Auto Analysis. [365831, 367479]
- Wants to use global array variables. [367474]
- Wants to show analysis parameters to Test Result list. [367480]
- Additional filter functions on Test Result Data Filter dialog. [367481]
- Context menu on Data Display. [397931]
- Wants to change list display location. [397972]
- Wants to save in Microsoft Excel format. [400555, 534479]
- One touch auto-export button on Test Result. [478784]
- Difference function (A(n)-A(n-1)) for an array data. [494106]
- Wants Ratio(A) function to exit I/V-t sampling test on TDDB measurement. [505812]

Bug Fixes

- Fixed: [367473] Difficult to find Excel Export menu.
- Fixed: [397932] Wants to unlock workspace temporarily (and lock it again) on saving operations.
- Fixed: [397933] The menu trees for Test Results are too complex.
- Fixed: [504307] Unexpected error message is shown after canceling Test Results Data Filter dialog with empty count strings.
- Fixed: [504454] Unexpected ArgumentOutOfRangeException on filtering Test Results.
- Fixed: [544211] Unexpected interpolation result on cursor analysis.
- Fixed: [550876] AutoAnalysis function is not working if the marker and Line equation are different.
- Fixed: [558082] Incorrect measurement values are shown for E5260A/70B on European culture.
- Fixed: [559981] Unexpected current sweep result on B2900A tracer test.
- – [565198] E5280A/81A cannot be used on Offline Configuration.

Version 6.1.1830.2880

Released Date:	9 Aug. 2018
File Name:	EE_for_PC_6.1.1830.2880.zip

Bug Fixes

- Fixed: [520799] EasyEXPERT has stopped working during remote control.
- Fixed: [532475] Unexpected automatic export is performed on recalling Test Result.
- Fixed: [533032] Unexpected timeout error on GPIB I/O.
- Fixed: [536020] Unexpected measured value resolution on E5270B.
- Fixed: [537303] EasyEXPERT GPIBIO function doesn't show a part of setting information.
- Fixed: [537609] E5270B standby mode does not work.
- Fixed: [539845] The maximum viewable test result records is limited to 5000.

- Fixed: [540051] External Trigger measurement doesn't synchronize with I/V-t sampling as start trigger by FLEX Service on B1500A.
- Fixed: [541229] Cannot detect UHV when the firmware revision is A.06.01.2015.1112 or prior.
- Fixed: [546782] 10 nA range is not available for B291XA right after recalling Classic Test Setup from My Favorite.
- Fixed: [546878] Apply is not shown in Classic Test Function tab from EasyEXPERT 6.X.
- Fixed: [552912] Unexpected scroll/selection result on Test Definition Editor.

Version 6.1.1742.9630

Released Date:	28 Nov. 2017
File Name:	EE_for_PC_6.1.1742.9630.rev2.zip

Bug Fixes

- Fixed: [520373] Read-only workspace is unexpectedly unlocked when the password dialog is canceled.
- Fixed: [520799] EasyEXPERT has stopped working during remote control.
- Fixed: [522756] Unexpected workspace selection on Workspace Management dialog.
- Fixed: [523559] Cannot use Calibration tool.
- Fixed: [524048] Extreme long measurement time on I/V-t Sampling.
- Fixed: [527415] Cannot get expanded application test results by :RES:FET:SIBL?.
- Fixed: [527535] Hangs up on renaming setup names on Organize Preset Group dialog.
- Fixed: [532394] Unexpected 'Verified' is shown for GPIB connections on Communication dialog.
- Fixed: [533032] Unexpected timeout error on GPIB I/O.

Version 6.1.1716.5160

Released Date:	29 May. 2017
File Name:	For_PC_6.1.1716.5160.zip

New Features and Enhancements

- B2900A LAN/USB connection support. [471178]

Bug Fixes

- Fixed: [494370] Extreme wait time between B1500A and Cascade Summit 12000 Probe Station during Subsite Moves.
- Fixed: [494401] Unexpected remoting exceptions during quick test.
- Fixed: [495492] FLEX doesn't read the data for external triggered measurement.
- Fixed: [495849] Unexpected OutOfMemoryException on importing large amount of test records.
- Fixed: [503768] No GPIB interface is listed on Execution Mode dialog when using IO Libraries Suite 2017.
- Fixed: [503864] Unexpected OutOfMemoryException on EasyEXPERT remote control.

Version 6.1.1649.6500

Released Date:	2 Feb. 2017
File Name:	For_PC_6.1.1649.6500.zip

Bug Fixes

- Fixed: [205523] Wants to highlight the measurement result row corresponds to the marker.
- Fixed: [375623] Unexpected exception occurs on Windows log-off or shutdown.
- Fixed: [375761] Unexpected exception occurs on Windows log-off or shutdown.
- Fixed: [394347] Unexpected overlay on Y axis title and scale labels.
- Fixed: [431041] A vertical axis variable is changed to another variable by adding new SMU to a sample setup on Tracer Test.
- Fixed: [436804] Unexpected parameter change occurs on closing/saving a test definition.
- Fixed: [453558] Unexpected auto-scaling when Target Axis is set to All Axes.
- Fixed: [453564] Unexpected auto-scaling on Trace Test.
- Fixed: [477444] Unexpected exception occurs on EasyEXPERT start-up.
- Fixed: [479204] Unexpected image files are saved by auto-export.

- Fixed: [481204] Cannot find Thyristor application tests.
- Fixed: [486035] I/V-t Sampling measurement may hangs or returns unexpected result on EasyEXPERT for PC.
- Fixed: [493285] Cannot restore Multi Channel I/V Sweep result.
- Fixed: [493324] FlexGUI may not be shown even if EasyEXPERT for PC is connected.

Version 6.1.1616.3825

Released Date:	23 May. 2016
File Name:	EasyEXPERT_for_PC_6116163825.zip

Bug Fixes

- Fixed: [431011] Auto scaling options are overwritten on every tests.
- Fixed: [441362] Unexpected exception on moving a Quick Test item.
- Fixed: [447193] Auto scaling options are overwritten on every tests.
- Fixed: [448952] Gate Charge configuration is not applied automatically on B1506A-H51.
- Fixed: [451733] Indicator may not be shown for read-only workspaces.
- Fixed: [451790] Slow operation response for many My Favorite Setup groups.
- Fixed: [452547] Improper descriptions in B2900A application test definitions.
- Fixed: [454103] Cannot use variable/expression for VAR2 compliance on B2900A.
- Fixed: [454324] Unexpected error message is shown when "Organize My Favorites" function is selected.
- Fixed: [454462] Workspace management buttons are disabled unexpectedly.
- Fixed: [454956] My favorite application tests can be executed without E5260A/70B/B2900A license.
- Fixed: [455823] Interlacing does not work on repetitive B2900A Tracer Test.
- Fixed: [455973] Unexpected exception occurs on repetitive measurement.
- Fixed: [464154] Configuration dialog hangs up after SMU zero cancel measurement.

Version 6.1.1550.2150

Released Date:	9 Feb 2016
File Name:	For_PC_6.1.1550.2150.zip

New Features and Enhancements

- B1506A-H20/H50/H70 support
- inTEST HP289-PM Thermal Plate GPIB control Application Test for B1505A/B1506A
- E526xA/70B Tracer Test support
- B2900A Classic Test support
- B2900A Tracer Test support
- [397932] Wants to open locked workspace via "read-only".
- [397967] Wants to show Display Setup dialog by double-clicking X/Y axis.
- [397969] Wants to draw a line with plots.
- [413540] [N1274A Support] IV path configuration Application Test for use in Quick Test.
- [435394] [Gate Charge] Support of displaying Id-Qg characteristics.
- [435315] [N1272A Support] Ciss-Vgs and Cies-Vge Application Tests are to be added.

Bug Fixes

- Fixed: [378876] Cannot set focus to Specification tab by tab key on Test Definition window.
- Fixed: [378877] EasyEXPERT is not shown to ALT+Tab switcher when Test Definition window is shown.
- Fixed: [429573] [Gate Charge] Drain series resistor for HVSMU is to be made off while measurement and to be restored after measurement.
- Fixed: [430420] Unexpected "not same dimension error" on Tracer Test.
- Fixed: [430727] Hangs up when arithmetic operation result contains an infinity.
- Fixed: [431037] WGFMU PATTERN EDITOR 4CH on the Group+ has "Preliminary Revision".
- Fixed: [432116] Application Test contents are not displayed.
- Fixed: [432118] [Gate Charge] Correction model is to be changed as residual resistance is placed between parasitic capacitance and DUT.

- Fixed: [432960] [Gate Charge] Key setup parameters and other detailed setup parameters are to be separated well.
- Fixed: [434233] [N1265A/N1266A Support] Failure of UHCU/HVMCU is to be reported at each time of applying configuration.
- Fixed: [436021] Incorrect description for lastValid() and lastValid2() in online help file.
- Fixed: [437190] [Data display] Zoom function works on the outside of graph.
- Fixed: [446647] No interlock open error message on E5260A/E5262A/E5263A/E5270B.
- Fixed: [447191] Toolbar layout is lost.
- Fixed: [448021] Unexpected exception occurs intermittently during measurements.
- Fixed: [448209] Unexpected exception occurs on Tracer Test run-time auto scaling.
- Fixed: [449386] Unexpected exception occurs on Data Display when all Y axes were deleted by Display Setup.
- Fixed: [449387] Unexpected exception occurs on exporting to Excel from Data Display shown by preview window.

Version 6.0.1534.4670

Released Date:	8 Sep, 2015
File Name:	For_PC_6.0.1534.4670.zip

New Features and Enhancements

- 4155/56 end-of-support message box is shown when starting EasyEXPERT with 4155/56. [381053]

Bug Fixes

- Fixed: [378489] Unexpected target model selection on "Target Model and Area of Interest" dialog.
- Fixed: [378806] Cannot select all items by [Results] - [Select All] menu.
- Fixed: [394408] Unexpected exception occurs on "Repeat Measurement Setup" and "Thermo-trigger List" dialogues.
- Fixed: [396696] Automatic image export fails.

- Fixed: [396697] Unexpected image is captured by [File]-[Save Image...] on Data Display.
- Fixed: [396698] Wants to edit locked My Favorite group without unlocking.
- Fixed: [396699] Can edit locked My Favorite group without unlocking.
- Fixed: [396781] Incorrect revision number in the release note.
- Fixed: [398193] Cannot open the workspace when it contains matrix compensation data.
- Fixed: [399434] Execution of Application Test with Display Data Setup may stall.
- Fixed: [400557] Unexpected 1st focus is set to Program List tab.
- Fixed: [407437] Fails to update from A.03.11 or prior.
- Fixed: [419438] E5260A/62A/63A/70B don't work with online mode even if B1500A/05A license was installed.
- Fixed: [420603] Switching matrix configuration is not restored.
- Fixed: [420740] Unexpected license error on E5260A/70B configuration dialog.
- Fixed: [428780] Incorrect current range candidates and maximum current check for E5281A.
- Fixed: [428782] Unexpected target model is shown to "Target Model and Area of Interest" dialog.
- Fixed: [429002] Cannot configure high speed ADC for E5260A/62A/63A.
- Fixed: [429758] Unexpected vertical scrolling on Program List tab.
- Fixed: [430033] Unexpected "Reset Window Layout" result on Test Definition window.
- Fixed: [9618] [DR15I-008] Data corrupted errors when automating B1530A WGFMU.

Version 6.0.1520.5030

Released Date:	1 Jun. 2015
File Name:	EasyEXPERT_PC_6.0.1520.5030.zip

New Features and Enhancements

- Gate Charge Adapter configuration support (B1505A/B1506A)
    - N1259A Opt014
    - N1265A Opt014

    - N1274A
    - N1275A
    - B1506A OptF14
- Multi HVSMU support (B1505A)
- New application test definitions (B1505A/B1506A/B1507A)
    - Gate charge measurement
    - Thermostream control
    - N1272A
    - Multi HVSMU
- Enhanced features and improved usability allow anyone to quick obtain the desired result.
- Take full advantage of the analyzer's powerful measurement and analysis capabilities from the lab to the office.
- Accelerate inter-departmental cooperation through free software deployment and user data protection.
- Offering support across the Keysight analyzer series for more flexibility and scalability according to your needs.

Bug Fixes

- Fixed: [373386] Cannot configure GPIB timeout by a variable.
- Fixed: [373409] Unexpected GPIB timeout on external equipment control.
- Fixed: [374739] Cannot configure fixtures when it is not turned on before opening a workspace.
- Fixed: [375838] Unexpected target model list update after selecting.
- Fixed: [378230] Unexpected exception on Data Display Y axes control.
- Fixed: [386884] Incorrect measurement unit for Rds parameter in Vds-Vgs application test.
- Fixed: [9554] [DR15I-004] Wrong calculation of Vds step in PowerMOSFET/Id-Vgs and Vce step in IGBT/Ic-Vge.

Version A.05.61.2014.1210

Released Date:	5 Feb. 2015
File Name:	B1500_A.05.61.2014.1210.Desktop.zip

New Features and Enhancements

- [9489] [Thermo-Trigger] Temperature range for trigger condition is to be extended.

Bug Fixes

- Fixed: [9458] Measurement may be stopped due to Data Display error.
- Fixed: [9499] [Remote Control] Recalling setup from my favorite setup causes hung-up in case of Tracer Test mode.
- Fixed: [9500] [Auto Analysis] Interpolation is turned off when test result is recalled.

Version A.05.60.2014.0926

Released Date:	4 Nov. 2014
File Name:	B1500_A.05.60.2014.0926.Desktop.zip

New Features and Enhancements

- B1513C support
- B1506A configuration support
- B1507A configuration support
- Keysight re-branding
- [8958] [Tracer Test] Change to enable marker and read-out during repeat measurement.
- [9008] [Tracer Test] Option to limit output polarity according to axis indication polarity.
- [9022] [Tracer Test] Maximum number of arithmetic operation is to be enhanced.
- [9037] [I/V List Sweep] Support of Multi-Channel Pulse Sweep
- [9042] [Tracer Test] Support of customizing setup templates
- [9045] [Test Result Export] Guide to Folder Export for multiple test results
- [9046] [Tracer Test] Support of scaling by changing per division.

- [9055] [Tracer Test] Option to save data of all channels and arithmetic operations.
- [9063] [Tracer Test] Option for Classic Test conversion with fixed measurement range setting.
- [9066] [N1267A Support] Pulse version of Id-Vds Current Collapse is to be added in Application Library.
- [9067] [Oscilloscope View] Support of auto scale
- [9302] [Database] Need to improve database recovery utility.

Bug Fixes

- Fixed: [9019] [Quick Test] Unexpected error 111004 occurs for calling readThermometerOfN1265A() built-in function from Function Setup of Classic Test.
- Fixed: [9026] [Tracer Test] Vertical stacking of arithmetic operation panels causes null reference exception for creating or recalling another setup.
- Fixed: [9061] [N1265A Thermometer Support] Timeout error 103003 occurs for enabling thermometer of N1265A at the second of DIO daisy chain.
- Fixed: [9068] [DR13I-010] ASU S/N is not displayed for B1511B on EasyEXPERT Configuration Window.
- Fixed: [9070] [N1265A Thermometer Support] Reading of a thermometer may not be performed during Quick Test.
- Fixed: [9075] [Data Display] Recalling of appended test results may cause remoting exception.
- Fixed: [9090] [N1265A Thermometer Support] Cannot abort thermo-trigger immediately.
- Fixed: [9106] [DR14I-002] Error occurred when restoring the EasyEXPERT database folder.
- Fixed: [9157] [Workspace Import/Export] "The directory is not empty." error may be reported at the end of importing/exporting workspace (*.xws) while anti-virus software is running.
- Fixed: [9161] [B1500-60006 Touch Panel Support] Mouse click handling is to be replaced with mouse down handling.

Version A.05.50.2013.0426

Released Date:	12 Jun. 2013
File Name:	Desktop_EasyEXPERT_A.05.50.2013.0426_updater.zip

New Features and Enhancements

- B1511B support for B1500A
- B1511B/E5288A support for B1500A
- B1514A support for B1500A
- B1511B support for B1505A
- Contribution to Application Test Library
- [8986] [EasyEXPERT] New Features Advertisement
- [8987] [EasyEXERT] Remote Control Function
- [8988] [EasyEXPERT] Information Generation for Technical Support
- [8995] License for Agilent EasyEXPERT Extension
- [8996] Support of import and export of Workspace
- [8948] [Tracer Test] Existing traces are to be cleared at the start of measurement.
- [8965] [Tracer Test] Default interlacing for pulse mode VAR1 channel is to be 1.
- [8968] [Application Test] PowerMOSFET Cgs and IGBT Cge application tests are to be changed to sweep Drain-Source/Collector Emitter voltage.
- [8989] [I/V Sweep] Sweep points enhancement to 10,001 ptsNone.

Bug Fixes

- Fixed: [8961] [Oscilloscope View] Maximum setting for delay time is to be defined.
- Fixed: [8985] [EasyEPXERT] Memory leaks when repeating to open and close a workspace.
- Fixed: [8992] [DR13I-006] EasyEXPERT data display is not updated automatically.
- Fixed: [8993] [C-V Sweep] Model parameter name for L, Q, Y, B, and X are not saved in exported setup.
- Fixed: [8994] [N1265A Support] Unexpected error 105994 occurs for disabled assignment of Gate Control SMU which is assigned for N1266A or N1268A..

Version A.05.04.2013.0328

Released Date:	28 May. 2013
File Name:	Desktop_EasyEXPERT_A.05.04.2013.0328.zip

Bug Fixes

- Fixed: [8972] [Oscilloscope View] Delay may increase unexpectedly for each measurement in case of duration above 4ms.

Version A.05.03.2013.0124

Released Date:	Feb. 2013
File Name:	-

New Features and Enhancements

- [8932] [ER12I-149] EasyEXPERT: Readout function to refer the latest AutoAnalysis Result on ASSIGN.
- "Ic-Ib for Expanders" and "G-Plot for Expanders" are added in the PowerBJT category of Application Library.

Bug Fixes

- Fixed: [8752] EasyEXPERT database restoration may fail.
- Fixed: [8925] [N1268A Support] Unexpected error 1004 may occur depending on pulse base and peak settings.
- Fixed: [8927] [N1265A/N1266A/N1268A Support] Standby Channel Definition may be left disabled after losing communication with expanders.
- Fixed: [8929] [UHCU 500A Version Support] Recalling or importing fails for setups using UHCU of 500A version.
- Fixed: [8933] [N1267A Support] Time offset definition in Signal Monitor application tests for GaN Current Collapse is different from Oscilloscope View.
- Fixed: [8934] Error occurs for exporting test result of empty Tracer Test setup.
- Fixed: [8940] [Tracer Test] Changing IPULSE VAR2 channel to VAR1 channel may cause persistent error messaging.

- Fixed: [8944] [UHCU/HVMCU/UHVU Support] Power compliance for VAR2 channel is not based on measured values.

Version F.A.05.02.2012.1207

Released Date:	Jan. 2013
File Name:	-

Bug Fixes

- Fixed: [8929] [UHCU 500A Version Support] Recalling or importing fails for setups using UHCU of 500A version.

Version A.05.02.2012.1026

Released Date:	Dec. 2012
File Name:	-

Bug Fixes

- Fixed: [8839] [Oscilloscope View] Time domain may not be set to 5us/div by enter key.
- Fixed: [8850] [C-V Sweep] For imported C-V Sweep setup, CONST SMU channel source setting may be reset to 0 depending on the order in channel definition.
- Fixed: [8852] [N1267A Support] 0V is output for Gate instead of GateOff setting for FET Current Collapse Signal Monitor Application Test.
- Fixed: [8855] [Classic Test] Channel Setting in Advanced Setup dialog may miss and duplicate SMU channels depending on GNDU order in Channel Definition.
- Fixed: [8856] [Database] database may corrupt by saving App Test Definition during measurement.
- Fixed: [8858] [EasyEXPERT for 415x] Error may occur with execution Application Test imported from Test Setup file.
- Fixed: [8862] SMU/PG Selector setting and ASU I/O Path setting are not restored at the opening of a workspace.
- Fixed: [8864] Recovery from non-numeric input for numeric field needs keyboard.

- Fixed: [8866] [Auto/Folder Export] Access Control List of index.txt is not derived from the target folder.
- Fixed: [8868] [N1268A Support] Diagnosis may end up with timeout error in case of wrong V Control SMU connection.
- Fixed: [8870] [Oscilloscope View] Sampling setup is disabled in case that only arithmetic operation data is selected.
- Fixed: [8873] [Tracer Test] Axis setting dialog may not appear appropriate position in case of Desktop version.
- Fixed: [8904] [Tracer Test] User Function converted from arithmetic operation with right-hand side operand of signed literal constant is invalid.

Version A.05.01.2012.0901

Released Date:	Oct. 2012
File Name:	-

New Features and Enhancements

- N1267A support for B1505A
- N1265A diagnosis
- N1268A diagnosisDual HCSMU Combination support

Bug Fixes

- Fixed: [8756] [Tracer Test] Specified minimum value of scale may not be restored from my favorite setup.
- Fixed: [8779] [N1265A Support] Thermo-trigger does not refer latest temperature.
- Fixed: [8783] [Database Restoration] Access Permission of Database changes.
- Fixed: [8786] [Oscilloscope View] Error dialog persists for time scale input of wrong format.
- Fixed: [8789] [Multi Channel I/V Sweep] Incorrect Japanese error message for error 105940.
- Fixed: [8790] [B1511A Support] MPSMU is to be supported in Application Tests for B1505A.

- Fixed: [8796] [N1265A Thermometer Support] Thermo-trigger setting GUI on Repeat Measurement Setup is to be disabled in case of other than B1505A.
- Fixed: [8802] [N1265A Support] Performing self-test resets default output.
- Fixed: [8815] [Oscilloscope View] Time domain scale setting dialog persists after switching to Test Modes other than Tracer Test Mode.
- Fixed: [8824] [N1265A Support] Wrong error handling for trial of self-calibration for self-test failed UHCU.

Version A.05.00.2012.0630

Released Date:	Aug. 2012
File Name:	-

New Features and Enhancements

- B1511A support for B1505A
- B1513B support for B1505A
- B1514A support for B1505A
- N1265A support for B1505A
- N1266A support for B1505A
- N1268A support for B1505A
- Oscilloscope View in Tracer Test mode
- Pulse measurement delay in Tracer Test mode
- Hold time for VAR1 and VAR2 in Tracer Test mode.
- Thermotrigger using thermometer of N1265A.
- [8614] [Advertisement Support] Agilent Logo is to be placed in graph image dump.
- [8622] [Multi Channel I/V Sweep] Measurement delay setting is to be supported in case of single pulse channel.
- [8625] [Tracer Test] Support of binomial operations of addition, subtraction, multiplication and division.
- [8632] [Data Display] Support of optional setup parameter summary on graph view

- [8637] [B1505A] QSCV application test is to be visible also in case of B1505A.
- [8477] [EasyEXPERT/Desktop EasyEXPERT] should show appropriate error massage that shows it does not support 'Switch User'.
- [8539] [Tracer Test] Fixed scaling is to be saved and restored.
- [8676] [Auto/Folder Export] Flag and Remarks of test result are to be included in file name of custom format.

Bug Fixes

- Fixed: [8492] [I/V Sweep] Immediate value of VAR1 step width is not applied in case of assigning non-immediate expression of Start/Stop.
- Fixed: [8581] [Tracer Test] Displayed value of pulse duration is not updated according to current pulse peak value.
- Fixed: [8657] [Tracer Test] Trace including NaN saved in XMLSS format cannot be restored due to parsing error.
- Fixed: [8673] [Tracer Test] Data unit may not correspond to axis assignment change in case of fixed scaling.
- Fixed: [8700] [Tracer Test] Conversion to Multi Channel I/V Sweep Classic Test Setup may fail.
- Fixed: [8736] [Licensing] Ejecting network interface causes crash of License Management Tool at its invocation.

Version A.04.21.2012.0413

Released Date:	Jun. 2012
File Name:	-

Bug Fixes

- Fixed: [4973] Readout function (@MX, @MY) does not return marker position when Tangent/Regression analysis line is used in fixed mode.
- Fixed: [8383] [WES7] Ejecting USB 2.0 device while measurement may cause timeout error.

- Fixed: [8514] [Tracer Test] Pulse period setting in recalled/imported setup may be prolonged.
- Fixed: [8595] [MM10] HVSMU may not output negative current for voltage compliance setting above 1500V.
- Fixed: [8630] EasyEXPERT may not terminate properly with shutdown by power button.

Version A.04.20.2011.0823

Released Date:	Oct. 2012
File Name:	-

New Features and Enhancements

- Windows version of B1500A/B1505A is changed to Windows Embedded Standard 7.
- Windows 7 32-bit version and 64-bit version are supported for Desktop EasyEXPERT.
- [8317] Blinking of ALWG Pattern Editor for adding a new point is to be suppressed.
- [8344] [I/V-t Sampling] Data transfer in High-Speed Sampling mode is to be bulky.

Bug Fixes

- Fixed: [8213] [Multi Channel I/V Sweep] Unexpected error 105940 may occur even in case of single pulse channel setting.
- Fixed: [8216] [Preset Group] Even in case of single preset group, copy/move button is enabled in Organize Preset Group dialog.
- Fixed: [8286] [Tracer Test] Setup templates is to be updated for Dual HCSMU.
- Fixed: [8306] Hung-up after aborting high speed sampling without recoding test result.
- Fixed: [8314] Cannot use Shift/Ctrl function with scroll bar on list view of quick test.
- Fixed: [8325] 'Program Compatibility Assistant' Dialog appears when SetupConverterW is terminated.
- Fixed: [8328] Test Definition Editor blinks when resize window.
- Fixed: [8329] Minimum size and anchor setting is unnatural on test specification tab.

Version A.04.11.2010.1209

Released Date:	Jan. 2011
File Name:	-

Bug Fixes

- Fixed: [8030] [DR09I-046] B1500A: Data saved as "CSV" is actually tab separated values on the Tracer Test.
- Fixed: [8128] [DHC] Error 130011 occurs for importing Classic Test setup with power compliance setting above 40W (DC) or 400W (Pulse).
- Fixed: [8132] [DHC] Loading workspace with Dual HCSMU Configuration fails for failed HCSMU.
- Fixed: [8149] [Tracer Test] In case of Dual Polarity Sweep, trace of Single Measurement after Repeat Measurement may not appear.
- Fixed: [8151] [I/V Sweep] Pulse width check may be bypassed for unit change in channel definition.
- Fixed: [8161] [Tracer Test] In case of fixed pulse period setting, error 105001 may occur for added channel due to its pulse width not conforming to the pulse period.
- Fixed: [8169] [WOW64 Support] No GPIB interface option appears for Desktop EasyEXPERT due to WOW64 registry redirection.
- Fixed: [8170] [Tracer Test] Reading reference trace in XMLSS format skips each first sample for the second or greater VAR2 step.
- Fixed: [8190] [Tracer Test] Setup template for B1500A MOSFET ID(off)-VDS has duplicate channel assignments.

Version A.04.10.2010.0528

Released Date:	Jul. 2011
File Name:	-

New Features and Enhancements

- Dual HCSMU Combination support
- [ER09I-073] B150xA: Dual Polarity Sweep support in Tracer Test mode.
- [8068] ER09I-04 B1500A: B1500A R-I Kelvin Application Library enhance request Auto forwarded by a Rule.

Bug Fixes

- Fixed: [8028] [DR10I-001] B1500A: Input Range/Resolution of Id_at_Vth is not appropriate.
- Fixed: [8020] [MFCMU] Auto ranging may end up in not optimal range due to improper time window for status latching.
- Fixed: [8062] [Tracer Test] Auto adjustment of pulse period and width does not work for HCSMU 20A range constraints.
- Fixed: [8091] [HVSMU] *TST? does not report failure in Osc. Detector Test.
- Fixed: [8094] [Multi Channel Pulse] Wrong value and X status may occur when pulse width is set longer than 500ms.
- Fixed: [8113] [C-V Sweep, Direct Control] Internal conversion between impedance and admittance may cause improper rounding.
- Fixed: [8114] [Tracer Test] Saving compressed trace list (.gtr) to a removable device may prevent safe removal of the device.
- Fixed: [8115] [Tracer Test] Saving reference trace to existing file may result corrupt trace file due to no truncating of the file.

Version A.04.03.2010.0130

Released Date:	Mar. 2010
File Name:	-

Bug Fixes

- Fixed: [8038] For some culture/locale settings, display of SMU Output Setting Limits does not correspond to the actual settings.

- Fixed: [8039] [Tracer Test] For some culture/locale settings, reading traces from .csv or .gtr file may not be successful.

Version P.A.04.02.2009.1216

Released Date:	Jan. 2010
File Name:	-

Bug Fixes

- Fixed: [8033] For some localizations of Windows XP, installation of Desktop EasyEXPERT may be unsuccessful and unable to start by user account without administrators' privilege.
- Fixed: [8037] Installer fails in updating firmware from P.A.04.00.2009.0626

Version F.A.04.02.2009.1216

Released Date:	Feb. 2010
File Name:	-

Bug Fixes

- Fixed: [8021] For some localizations of Windows XP, installation of Desktop EasyEXPERT may be unsuccessful and unable to start.

Version A.04.02.2009.1027

Released Date:	Dec. 2009
File Name:	-

Bug Fixes

- Fixed: [7996] [DR09I-041] B1500A: GPIB I/O ReadValue operation has a gap from User's Guide.
- \- [8001] [DR09I-043] B1500A: The calculation for D is wrong in Generic C-f and Generic C-t.

- - [8008] [App. Lib.] Utility::QSCV C Offset Meas should not be listed for B1505A.
- - [8013] [Data Display] For clipboard copy of graph image, MSPAINT.EXE may not draw traces containing scoped-out point.
- - [8014] [Tracer Test] Dead time between sweeps may vary due to internal time-out for data reading.

Version A.04.01.2009.0810

Released Date:	Oct. 2009
File Name:	-

Bug Fixes

- Fixed: - [7493] [Auto Analysis] Nested evaluation of read-out function in analysis function definition malfunctions.
- Fixed: - [7570] [Instrumentation] Source data resolution in case of voltage log sweep is to correspond to fixed output ranging.
- Fixed: - [7693] [Tracer Test] Improper axis range for sweep source data in case of bipolar axis setting and Data Display of corresponding test result.
- Fixed: - [7906] [DR09I-027] Error 114101 occurs for exporting test result with multi-byte setup name as CSV.
- Fixed: - [7911] Sample application test "Vth gmMax and Id" is not integrated.
- Fixed: - [7915] EasyEXPERT error occurs when the channel mapping is set by ACH FLEX command.
- Fixed: - [7916] [DR09I-032] Error 122014 occurs while running Reliability::Charge Pumping application test in case of enabling allocation of Data Display for each test.
- Fixed: - [7917] [DR09I-030] The output waveform of Reliability::Charge Pumping application test is different from application note 5964-2195E.
- Fixed: - [7922] [Ana.Op] NullReferenceException may be thrown for print preview operation of Data Display.
- Fixed: - [7923] [Multi Channel I/V Sweep] Unexpected error 105001 corresponding to FLEX error 1008 for pulsed sweep may occur without pulsed channel.
- Fixed: - [7932] [Tracer Test] Remaining data is wrong, when the tracer test is aborted by INTLK open.

- Fixed: - [7943] [Tracer Test] Change of SMU output range due to power compliance setting is not displayed on GUI.
- Fixed: - [7944] [Tracer Test] Sweep range of recalled or converted setup is changed regardless of power compliance setting.
- Fixed: - [7948] [DR09I-033] Read-out function @L<m>Y<n> may return incorrect value.
- Fixed: - [7951] DR-09I-036 [Defect Report] B1500A: QuickTest is not supported on EasyEXPERT 4.0 offline operation.
- Fixed: - [7953] [N1258A Support] Status LED is turned on after diagnosing regardless of the setting before diagnosing.
- Fixed: - [7954] [N1258A Support] Status LED should be turned off while diagnosing.
- Fixed: - [7956] [App. Lib.] Sweep should continue at any measurement status for off-leak and breakdown measurements.
- Fixed: - [7957] [App. Lib.] Default delay time of C-V Sweep using HV Bias Tee should be 80ms.
- Fixed: - [7958] [App. Lib.] HR ADC is preferable for leak or breakdown measurement considering the use of HPSMU.
- Fixed: - [7973] [Tracer Test] Error 105001 due to F/W error 130 may occur for inconsistency between VAR1 Start/Stop and Power Comp.
- Fixed: - [7984] [App. Lib.] Interpolation should be on for PowerMOSFET::Id(off)-Vds.
- Fixed: - [7985] [Tracer Test] Error 105001 due to firmware error 130 may occur for switching between staircase and log sweep.
- Fixed: - [7986] [Tracer Test] Erased tracking trace remains on graph until next measurement.
- Fixed: - [7987] [Classic Test] Unexpected error 105001 due to firmware error 1002 occurs for HCSMU channel with pulse width setting exceeding 1ms with AUTO period and current setting exceeding 1A.
- Fixed: - [7990] [Tracer Test] Bias settings may not be exported in correct order.
- Fixed: - [7993] Ic-Vce(PowerBJT) application test with manual pulse period setting encounters unexpected exception.

Version A.04.00.2009.0609

Released Date:	Aug. 2009
File Name:	-

New Features and Enhancements

- HCSMU, HVSMU and Module Selector Support
- Auto Start of EasyEXPERT
- Auto Selection of Workspace
- Interlock Circuit Diagnosis
- SMU Output Setting Limits for B1505A
- Power Device Application Library for B1505A
- SMU voltage sweep in C-V Sweep Classic Test
- Multi-channel pulsed sweep in Multi-Channel I/V Sweep Classic Test
- Tracer Test
- [ER06-27] Duplicate the line of Test Parameter Definition. [ID 7001]
- [ER06-28] Variable list is shown when editing the Test Contents. [ID 7002]
- [ER07-83] Want data save (Record) on/off capability in each items in the quick test. [ID 7003]
- [ER08-23] Remember graph window settings in EasyEXPERT. [ID 7004]
- [ER08-33] Preset group import/export procedure is not useful. [ID 7005]
- [ER08-35,37] Want to set ADC/Integ setting for SMU Pulse. [ID 7245]
- [ER08-83] Add counter reset option in repeat measurement window and in main window of EasyEXPERT. [ID 7006]
- [ER08I-116] EasyEXPERT programming environment is poorly documented and difficult to use. [ID 7234]

Bug Fixes

- Fixed: [DR08I-23] GPIB Timeout Error Occur at opening workspace and unexpected TooManyWorkspaceException is thrown for retrying opening workspace. [ID 7034]
- Fixed: [DR09I-019] Easy EXPERT BVdss application has bug. [ID 7685]

- Fixed: [DR09I-024] Fast BTI application test failed when the SICL ID is set as hpib7. [ID 7848]

Version A.03.20.2008.1030

Released Date:	Dec. 2009
File Name:	-

New Features and Enhancements

- WGFMU Support [ID 6997]
- \- Supporting self-testing and self-calibration
- \- Providing application libraries using WGFMU
- Windows Vista Support [ID 6994]
- Incremental Search for Application Test Library [ID 7045]
- License Management Tool [ID 7104]
- Built-in function string() accepts string type. [ID 6963]
- Database move windows is automatically closed. [ID 6971]
- Data Vector Edit Dialog supports row insert function. [ID 6972]
- Limitation of total data points is relaxed with sweep measurement. [ID 6973]
- Last used workspace selection is restored. [ID 6974]
- Labels are improved to be more comprehensive in GPIB I/O Plug-in. [ID 6975]
- Labels are improved to be more comprehensive in Text File Export setting. [ID 6977]
- Analyzer model can be selected in Desktop EasyEXPERT when Agilent IO Library Suite is not installed. [ID 6998]
- HRSMU serial which is used for calibration is shown in Notes. [ID 7183]

Bug Fixes

- Fixed: Fixed: B1500A the sweep is finished before reaching VAR2 stop value. [ID 6797]
- Fixed: Timing on the fly NBTI failed if the initial stress > 500 sec [ID 6941]

- Fixed: Error message may be displayed when "FIXED" mode is chosen in SMU Range Setup dialog. [ID 6956]
- Fixed: Desktop EasyEXPERT cannot access to 415x. [ID 6967]

Version P.A.03.11.2008.0903

Released Date:	Nov. 2008
File Name:	-

Bug Fixes

- Fixed: EasyEXPERT A.03.11 cannot control 11731A switch controller which is used in PIV solution by GPIB I/O. [ID 7057]
- Fixed: EasyEXPERT A.03.11 cannot read data from 3458A multimeter by GPIB I/O. [ID 7115]

Version A.03.11.2007.0611

Released Date:	Aug. 2007
File Name:	-

New Features and Enhancements

- Faster and robust text file exporting with flexible formatting options.
- Agilent 415xB/C Parametric Analyzer Support Enhancements:
- Range Change Rule support Improvements:
- More robust database management
- Faster installation and start-up
- Faster data storage
- Faster turnaround time at automated repeating looping
- Improved Data Display response
- Workspace name is shown in EasyEXPERT main GUI.
- Run Option setting is retained in Workspace context.

Bug Fixes

- Fixed: Wrong Amplitude(V) scale appears in ALWG Pattern Editor. [ID 6526]
- Fixed: Parameter value may not be restored when recalling a test result. [ID 6664]
- Fixed: USB memory device cannot be removed after exporting test result into it by Export in My Format. [ID 6666]
- Fixed: Progress of SPGU Control may not reach 100 %. [ID 6774]
- Fixed: SMU/SPGU Calibration tab in Calibration dialog shall be renamed. [ID 6775]
- Fixed: Export in My Format dialog is displayed in the taskbar. [ID 6801]
- Fixed: Output file name and File Name Format are different. [ID 6812]
- Fixed: Default icon is used in Database Summary Report Dialog on task bar. [ID 6822]
- Fixed: Unexpected characters may be displayed in list view of Quick Test. [ID 6823]
- Fixed: "Display Data" does not work while long-time measurement is performed. [ID 6895]

Version A.03.10.2007.1112

Released Date:	Dec. 2007
File Name:	-

New Features and Enhancements

- Classic Tests Enhancements:
  - HV-SPGU Support
  - GNDU Support
- I/V-t Sampling Enhancements:
  - Stop Condition Support
- Switching Matrix Control Enhancements:
  - E5250A Switching Matrix Support (License option is required.)
- 16440A SMU/PG Selector Support
- Data Display Enhancements:

    - Multiple Data Display
    - Fixable Analysis Lines
- Agilent 415xB/C Parametric Analyzer Support Enhancements:
    - New Classic Test
        - I/V-t Sampling (License option is required.)
- Classic Tests Enhancements:
    - VSU/VMU Support (License option is required.)
    - PGU Support (License option is required.)
    - GNDU Support
- Graphical status indicator for remote control
- Utility to toggle Windows auto login.
- Page margin for printing is improved.

Bug Fixes

- Fixed: Prompt if there are unsaved texts and pointers on graph.
- Fixed: Improved resources assignment in Application Test
- Fixed: Subscript of pointer is not displayed in print preview. [ID 5988]
- Fixed: Intercept, Gradient field of Y Axis(Sub) is not initialized when Line1 is enabled. [ID 5998]
- Fixed: Information about Line may be corrupt after GraphPropertiesDialog is closed. [ID 6001]
- Fixed: Change in the order of Y axes causes elimination of Texts on graph. [ID 6024]
- Fixed: "Cancel Scaling" causes elimination of Texts and Pointers on graph. [ID 6038]
- Fixed: Auto scaling with LOG scale may not work properly. [ID 6247]
- Fixed: Delete All function in define vector editor does not work. [ID 6030]
- Fixed: Auto Analysis doesn't work for max() with After condition. [ID 6031]
- Fixed: "Tile Data Display" does not work property in Desktop EasyEXPERT. [ID 6245]

Version A.03.00.2007.0529

Released Date:	Jul. 2007
File Name:	-

New Features and Enhancements

- New Classic Tests
    - Multi-Channel I/V Sweep
    - I/V List Sweep
    - Direct Control
- Standby Function
- Agilent 415xB/C Parametric Analyzer support
- Data Display enhancements
    - Run Time Auto Scale
    - Pointers on graph
    - Texts on graph
    - Shared Y axis scale
    - Highlighting coordinate axes
    - Label at each major tick
    - Minor ticks on log scale axis in wider range
    - Resizable tick labels, legends and title
    - X/Y scales alignment between overlaid graphs
    - Direct input for gradient of lines
- Data Record ON/OFF function
- Test Results Data Export in Simple Data Format
- Layout dialog for Test Parameters in Application Test Definition

  Performance improvement in storeAt() built-in function
- Improved CMU calibration instructions
- Tiling Data Display windows with the same window size.

- Showing Cable length with model number and option in Switching Matrix
- CMU Compensation dialog.

Bug Fixes

- Fixed: Unpredictable order of data columns in CSV test results. [ID5547]
- Fixed: Maximum power compliance for MP/HRSMU is corrected by 2W from 4W. [ID5723]
- Fixed: Synchronous sweep channel outputs pulse base output for Pulse I/V Sweep. [ID5685]
- Fixed: Reference to external vector variable in User Function causes wrong evaluation result. [ID3980]
- Fixed: Log range in Display Setup is not adjusted to decade. [ID5517]

Version F.A.02.11.2006.1119

Released Date:	Jan. 2007
File Name:	-

Bug Fixes

- Fixed: Cannot overlay more than 3 Data Displays. [ID5385]
- Fixed: Desktop EasyEXPERT may halt for interlock open while holding bias between setup executions. [ID5433]
- Fixed: Cannot use the value of numeric variable with symbol in Direct Control.

Version F.A.02.11.2006.1025

Released Date:	Dec. 2006
File Name:	-

Bug Fixes

- Fixed: High speed I/V-t sampling may assert false ADC overflow status depending on the number of samples. [ID4744]

- Fixed: I/V Sweep with HRSMU may lose data depending on integ. time and delay settings. [ID5255]
- Fixed: Cannot adjust offline unit configuration to online one. [ID5372]
- Fixed: Usage of offline unit configuration:

  Copy C:\Documents and Settings\All Users\Application Data\Agilent Technologies, Inc\EasyEXPERT\UnitConfigB1500A.xml on B1500A to the same location on your PC on which Desktop EasyEXPERT operates offline.
- Fixed: Numerous fixes in Direct Control.

Version A.02.11.2006.0928

Released Date:	Nov. 2006
File Name:	-

New Features and Enhancements

- EasyEXPERT database maintenance
- Test Result Data Folder Export

Bug Fixes

- Fixed: Cannot correct data name duplication in C-V Sweep. [ID5010]
- Fixed: Tabs in Data Display may become invisible. [ID5048]
- Fixed: Cannot recall test results of application test with invalid axis setup. [ID5050]
- Fixed: Data Display may not update its graph for append measurement. [ID5056]
- Fixed: Quick Test operation may cause hung-up. [ID5081]
- Fixed: Cannot pass string variables to application test parameters without typical values. [ID5199]
- Fixed: Invalid ADC mode setting causes unexpected error messages. [ID5028]
- Fixed: After deleting all preset groups, setups stored in the default preset group become invisible. [ID5211]
- Fixed: Nested user functions may delay starting a measurement. [ID5260]

- Fixed: Fast, iterative line selection in program editor may cause an unexpected error (ObjectDisposedException). [ID5273]

Version 02.10.2006.0630

Released Date:	Aug. 2006
File Name:	-

New Features and Enhancements

- Impedance range setup in C-V Sweep
- CMU AC level/DC bias monitoring in C-V Sweep
- Categorized Application Test listing in Program Editor
- Progress indication and cancellation while deleting Test Results
- Import operation for plural test result files at once.
- Performance improvements in executing Quick Test, in recalling Test Setup from Preset Group
- Performance improvements of Data Display in switching tabbed pages and (real-time) data listing.
- Performance improvements in listing Application Tests for Categories, in setting up Application Test, in editing Application Test definition.
- Performance improvements in setting up Classic Test
- Scalability improvements in importing huge Test Results
- Progress/wait indication while loading Workspace and importing/exporting.
- Test Setup, Preset Group, Application Test definition and Test Results
- Performance improvements in sorting and filtering Test Result List

Bug Fixes

- Fixed: FLEX control sometimes hangs up when application measurement was stopped by Device Clear.

Version A.02.00.2006.0418

Released Date:	Jun. 2006
File Name:	-

Bug Fixes

- Fixed: Auto export function exports test results of application test in reverse order.
- Fixed: For I/V-t sampling using negative hold time, stepping position in source data series is incorrect in case of interval relaxation for monitor channel count.
- Fixed: Windows starts rebooting if FLEX command service receives any command while Agilent Connection Expert is opened.
- Fixed: Performance issues in storing, importing and exporting huge test results.
- Fixed: Cannot store nor recall empty test results.
- Fixed: Cannot duplicate setup with name of maximum length in preset group.
- Fixed: An error occurs for front key operation if options for an input field decrease.
- Fixed: Cosmetic defects in Data Display.

Version A.02.00.2006.0404

Released Date:	May. 2006
File Name:	-

New Features and Enhancements

- Auto Analysis in Classic Test
- B220xA support
- Bias Hold after Measurement
- Data Append
- Data Display enhancements
- dim1Size and dim2Size built-in functions
- I/V-t Sampling enhancements
- My Favorite Setup in Application Test Contents

- Post Analysis in Classic Test
- Prober Control A.02.00
- Quick Test
- Status Indicators
- Status LED Control (ASU/SCUU)
- SMU Zero Cancel
- Subsite Probing support.
- Test Results Data Auto Export

Bug Fixes

- Fixed: Change of a setup in test contents effects to its copy. [ID4110]
- Fixed: PGU control library does not work under some locale/culture settings. [ID4706]
- Fixed: Cannot apply change of User Function to Data Display after measurement. [ID4123]
- Fixed: Improvement of the usability of ASU which is not calibrated with HRSMU. [ID4124]
- Fixed: Enhancement of I/V-t sampling capabilities.

Version P.A.01.10.2005.1130

Released Date:	Dec. 2005
File Name:	-

Bug Fixes

- Fixed: If the read-out function is used for any parameter setting in a test setup, the display in the Data Display window will slow down. [CR26958]
- Fixed: The auto scale function in the Data Display window does not work when the maximum or minimum data in the graph data is less than 1.000000E-15. [CR27884]
- Fixed: If a variable name that is defined as string value in the imported test is set to a string parameter in the Test Definition window, an error occurs. [CR27990]
- Fixed: If the scale of the graph is changed in the Data Display window, the normal/gradient/regression lines and cursor will be corrupt. [CR27923]

- Fixed: When importing the I/V sweep setup with the double directional sweep, it will always be loaded as the single directional sweep. [CR28022]
- Fixed: When importing the test result of the I/V sweep test with the double directional sweep that has two or more VAR2 steps, it will be loaded as the result for the single directional sweep test. That is, the imported data is only the first half of the original result. [CR28023]
- Fixed: If the following combination of the sweep parameters is set and it is repeated in a loop, incorrect number of steps may be calculated and be applied.

  Start: low

  Stop: high

  Step: high - low [CR28169]
- Fixed: The auto scale function in the Data Display window does not work for data of both polarities in the log scale. [CR28346]
- Fixed: The sampling measurement has timing error for the last channel in its output sequence. Due to this error, extra overhead time around 50 ms is added before the bias hold time, and the channel starts to force the bias in the overhead time.
- Fixed: Since the time data does not consider the overhead time for the first measurement point, the time origin does not match with the start point of transition of the last channel's output. [CR28724]
- Fixed: If the default compliance value is selected in newly created I/V Sweep setup, unexpected compliance value is applied in the measurement. [CR28726]
- Fixed: For the pulsed sweep measurement, the pulsed sweep channel forces the start value of the sweep as the pulse base value of the initial bias level.
- Fixed: For the pulsed sweep measurement and measurements with the pulsed bias,

  The specified hold time is not applied.

  The Delay Time parameter is programmable, though it is invalid. [CR28752]
- Fixed: If the channel settings in the SMU Range Setup window meets both conditions below when importing an I/V Sweep or I/V-t sampling setup, the setting values are cleared and set to the default values.

  * The order of the channels in the SMU Range Setup window is different from the order of the channels in the Channel Setup screen.

  * The mode setting (I/IPULSE or V/VPULSE/COMMON) defined in the Channel

Setup screen for N-th channel in the SMU Range Setup window is different from the mode setting of N-th channel in the Channel Setup screen. [CR29007]

- Fixed: For the pulsed sweep measurement and measurements with pulsed bias, the following settings of the past that should not be used may cause an error, though they are not used in these measurements.

  * SMU Range Setup

  * ADC and Integration Time Setup [CR29008]

- Fixed: The auto scale function in the Data Display window does not work when the scale is log scale and the graph data of the maximum absolute value has negative polarity. [CR29304]

Version A.01.10

Released Date:	2005
File Name:	-

New Features and Enhancements

- Release for VS of B1500A.

Version A.01.02

Released Date:	2005
File Name:	-

Initial Release